

V.

Atty. Docket No. 8013-1070

PATENTS

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of

Takao ARAI

Confirmation No. 9250

GROUP 2826

Serial No. 09/963,533 Filed September 27, 2001

Examiner Johannes P. Mondt

SEMICONDUCTOR DEVICE INCLUDING A DEPLETION TYPE LATERAL MOSFET AND METHOD OF FORMING THE SAME

AMENDMENT

Commissioner for Patents

Washington, D.C. 20231

Sir:

Responsive to the Official Action of November 18, 2002, please amend the above-identified application as follows:

IN THE SPECIFICATION:

Page 5, replace the paragraph, beginning on line 9, bridging pages 5 and 6, as follows:

--With reference to FIG. 1I, the resist patterns 35, the gate electrodes 30a, 30b and 30c and the field oxide films 26 are used as masks for selective ion-implantation of arsenic as an n-type impurity into selected regions in the p-well region 25 and in the p+-type regions 34 at a high impurity concentration. used resist patterns 35 are completely removed. A heat treatment is then carried out for activation of the implanted impurity, thereby to selectively form n+-type regions 36a, 36b, 36c and 36d in the p-well region 25, and n+-type regions 36e in the p+-type